

TRANSMITTAL OF INFORMATION DISCLOSURE STATEMENT

(Under 37 CFR 1.97(b) or 1.97(c))

Docket No.

FIS920030275US1

OCT 14 2003

Re Application Of: **BARBARA A. AVERILL ET AL.**

Serial No.

10/605,530

Filing Date

10/06/2003

Examiner

NYA

Group Art Unit

NYA

Title: **SPECIFIC SITE BACKSIDE UNDERLAYING AND MICROMASKING METHOD FOR ELECTRICAL CHARACTERIZATION OF SEMICONDUCTOR DEVICES**

Address to:

Commissioner for Patents

P.O. Box 1450

Alexandria, VA 22313-1450

37 CFR 1.97(b)

1. ☒ The Information Disclosure Statement submitted herewith is being filed within three months of the filing of a national application other than a continued prosecution application under 37 CFR 1.53(d); within three months of the date of entry of the national stage as set forth in 37 CFR 1.491 in an international application; before the mailing of a first Office Action on the merits, or before the mailing of a first Office Action after the filing of a request for continued examination under 37 CFR 1.114.

37 CFR 1.97(c)

2. ☐ The Information Disclosure Statement submitted herewith is being filed after the period specified in 37 CFR 1.97(b), provided that the Information Disclosure Statement is filed before the mailing date of a Final Action under 37 CFR 1.113, a Notice of Allowance under 37 CFR 1.311, or an Action that otherwise closes prosecution in the application, and is accompanied by one of:
- ☐ the statement specified in 37 CFR 1.97(e);
- OR**
- ☐ the fee set forth in 37 CFR 1.17(p).

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(Only complete if Applicant elects to pay the fee set forth in 37 CFR 1.17(p))

- ☐ A check in the amount of _____ is attached.
- ☐ The Director is hereby authorized to charge and credit Deposit Account No. _____ as described below.
- ☐ Charge the amount of _____
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Jessica L. Walsh

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Signature

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Dated: October 10, 2003

CC:

INFORMATION DISCLOSURE CITATION

(Use several sheets if necessary)

Docket Number (Optional)

FIS920030275US1

Application Number

10/605,530

Applicant(s)

BARBARA A. AVERILL ET AL.

Filing Date

10/06/2003

Group Art Unit

NYA

U.S. PATENT DOCUMENTS

| EXAMINER INITIALS | REF | DOCUMENT NUMBER | DATE | NAME | CLASS | SUBCLASS | FILING DATE IF APPROPRIATE |
|----------------------|-----|-----------------|------|------|-------|----------|-------------------------------|
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FOREIGN PATENT DOCUMENTS

| | REF | DOCUMENT NUMBER | DATE | COUNTRY | CLASS | SUBCLASS | Translation | |
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OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

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|--|---|---|
| | 1 | http://www.hypervisioninc.com/procuz.htm |
| | 2 | M. Mahanpour et al.; "Die and Solder Ball Defect Inspection in Flip Chipped Packaged Devices;" found at http://www.fabtech.org/features/tap/articles/06.433.html |

EXAMINER

DATE CONSIDERED

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP Section 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.